


<b>Search Notes</b>  	<b>Application/Control No.</b>  10512075	<b>Applicant(s)/Patent Under Reexamination</b>  NAKACHI ET AL.
	<b>Examiner</b>  Nhon T Diep	<b>Art Unit</b>  2621

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
East Search	7/19/2009	ND
Consulted w/ Vo, 2621	1/27/2010	ND

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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